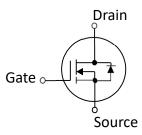


20V, 6A (1) N-Channel MOSFET

- Proprietary Trench Gate Device Design and Processes
- High Reliability Capability
- Sampled CP Probing and Inking





Electrical Characteristics in C/P Test (T」 at 25 ℃)						
Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Condition
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	20		_	٧	V _{GS} =0V, I _D =250μA
R _{DS(ON)}	Static Drain-Source On-Resistance	_		20	mΩ	$V_{GS} = 4.5V, I_D = 1A(2)$
R _{DS(ON)}	Static Drain-Source On-Resistance	_	_	34	mΩ	$V_{GS} = 2.5V, I_D = 1A(2)$
V _{GS (th)}	Gate Threshold Voltage	0.5	_	1.2	V	V _{DS} =V _{GS} , I _D =250µA
I _{DSS}	Drain-to-Source Leakage Current	_	_	1	μA	V _{DS} =20V, V _{GS} =0V
I _{GSS}	Gate-to-Source Leakage Current	-100		100	nA	V _{DS} =0V, V _{GS} =±12V
T _J , T _{STG}	Operating and Storage Temperature	-55℃ to 150℃ Max.				

Mechanical Data	Die Drawing		
Chip Size	688 µm X 991 µm	748.2	
Gate Pad Size	141 µm X 141 µm	482.5	
Source Pad Size	605 μm X 397 μm	140.95	
Scribe Line Width	60 µm	\$60	
Wafer Thickness	100 µm	577	
Wafer Diameter 200 mm		36	
Gross Die	73826 EA		
Source Metallization	Al-Cu (4µm typical)	274	
Drain Metallization Ti-Ni-Ag		140.95	
Passivation	N/A		
Recommended Storage Environment	Store in original container, in dry nitrogen, 6 months at ambient temperature of 23°C ± 3°C		

⁽¹⁾ This characteristic assumes the die is assembled in SOT23-6 package. Actual performance may degrade when assembled.

Address: Floor 5, D2 Building, No. 200, Linghu Blvd., Wuxi, Jiangshu, China

⁽²⁾ Pulse Width tp = < 1 mS, Duty Cycle < 2%.

SPQ20RN20W

Specific Assembly Info	Die Drawing	
Package Type	SOT23-6	748.2
Die Attach Method	ie Attach Method Soft solder	
Soft Solder Composition	Pb,Sn,Ag	274.95
Gate Wire Bonding	Cu, 1.65 mil x1	98
Source Wire Bonding	Cu, 1.65 mil x7	274.95
Molding Compound Manufacturer	G700HF	140.95
Solder Plating Composition	Pure Tin	

Position			Bonding Diagram Top View		
	X (um)	Y (um)	TOP		
ZERO	0	0	SS G4		
TOP	688.2	990.6	G3		
S1	41.6	41.6	56		
S2	646.6	438.7			
S3	646.6	163.75	.54		
S4	41.6	551.9			
S5	524.125	949	52*		
S6	671.6	974			
G1	671.6	16.6			
G2	530.125	157.55	\$3 •		
G3	530.125	833.05	S1 G1		
G4	671.6	974	ZERO		



SPQ20RN20W

Electrical Characteristics in F/P Test (T」at 25 ℃)						
Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Condition
I _{DSS}	Drain-to-Source Leakage Current	_		1	μA	V _{DS} =20V, V _{GS} =0V
I _{GSSF}	Gate-to-Source Leakage Current	_	_	100	nA	V _{DS} =0V, V _{GS} =+12V
I_{GSSR}	Gate-to-Source Leakage Current	-100	_	_	nA	V _{DS} =0V, V _{GS} =-12V
BV_DSS	Drain-Source Breakdown Voltage	20	_	_	V	V _{GS} =0V, I _D =250µA
BV_DSS	Drain-Source Breakdown Voltage	20	_	_	V	V _{GS} =0V, I _D =1mA
R _{DS(ON)}	Static Drain-Source On-Resistance	_	_	25	mΩ	V _{GS} =4.5V, I _D =1A
$V_{GS(th)}$	Gate Threshold Voltage	0.5	_	1.2	V	V _{DS} =V _{GS} , I _D =250μA
V _{SD}	Drain-Source Diode Forward Voltage			1.6	V	$V_{GS} = 0V$, $I_{SD} = 1A$
EAS test	IAS				А	V _{DD} =20V,Vgs=10V, RG=25ohm,L=0.5mH
T _J , T _{STG}	Operating and Storage Temperature	-55°ℂ to 150°ℂ Max.				

Disclaimer:

JUNSHINE does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information.

JUNSHINE reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

JUNSHINE makes no warranty, representation or guarantee regarding the suitability of the products for any particular purpose or the continuing production of any product. To the maximum extent permitted by applicable law, JUNSHINE disclaims (1) any and all liability arising out of the application or use of any product, (2) any and all liability, including without limitation special, consequential or incidental damages, and (3) any and all implied warranties, including warranties of fitness for particular purpose, non-infringement and merchantability.

JUNSHINE products, except as expressly indicated in writing, are not designed for use in medical, life-saving, or life-sustaining applications, or for any other application in which the failure of the JUNSHINE product could result in personal injury or death. Customers using or selling JUNSHINE products not expressly indicated for use in such applications do so at their own risks.

Resale of JUNSHINE products with statements different from or beyond the parameters stated by JUNSHINE for that product or service voids all express or implied warrantees for the associated JUNSHINE product or service and is unfair and deceptive business practice. JUNSHINE is not responsible or liable for any such statements.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted by this document or by any conduct of JUNSHINE. Product names and markings noted herein may be trademarks of their respective owners.

JUNSHINE IS A FULLY OWNED SUBSIDIARY OF Wuxi XICHANWEIXIN Semiconductor Co., Ltd.

Address: Floor 5, D2 Building, No. 200, Linghu Blvd., Wuxi, Jiangshu, China

Version: 1.0